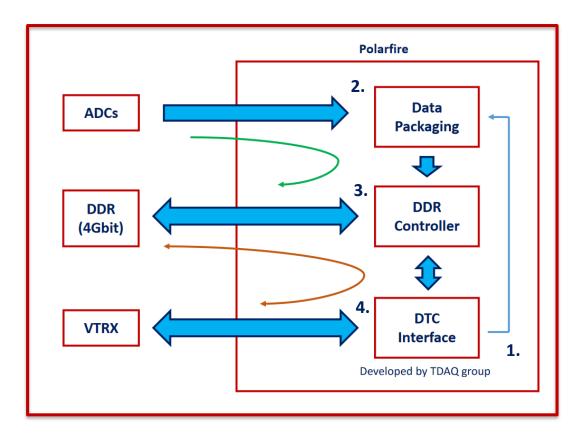


Status of DiRAC Firmware

Mu2e Italian Meeting September 03, 2020

S. Di Falco, A. Gioiosa, L. Morescalchi, E. Pedreschi, F. Spinella

Main Firmware Block Diagram



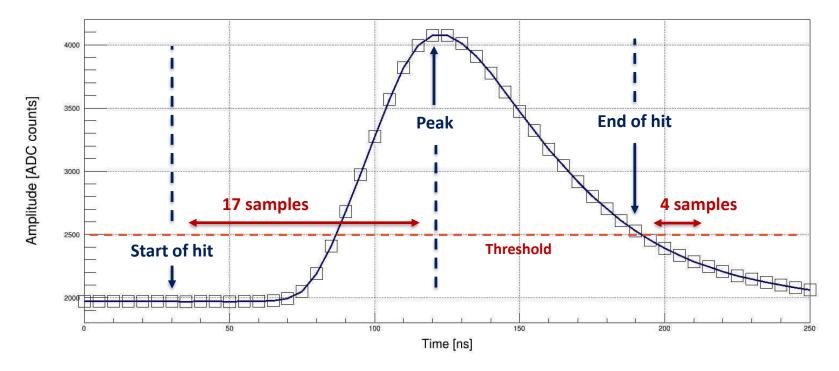
The slow control block is not shown..

- TDAQ sends Heartbeat packet that contains EVENT TAG and EVENT WINDOWS
- 2. DiRAC builds the calo hit applying a zero suppression and pre-processing data
- 3. Data are stored in the DDR
- TDAQ sends Data Request for a specific EVENT TAG, and DiRAC retrieve requested Data Packet from DDR and sends it out to DTC





Zero Suppression: Hit Definition



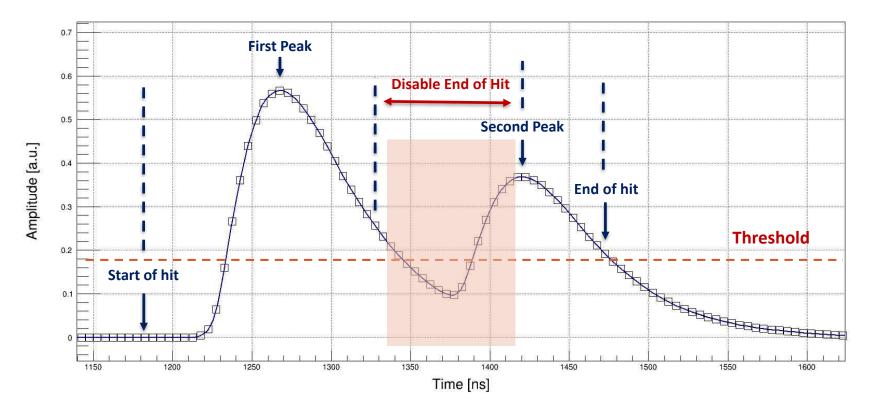
- An hit triggers when is found a peak over threshold and is composed of: ٠
 - 17 samples before the peak, to be sure to record the rising edge and the baseline level
 - A variable number of samples until the waveform goes under threshold for 4 consecutive samples





6/26/18

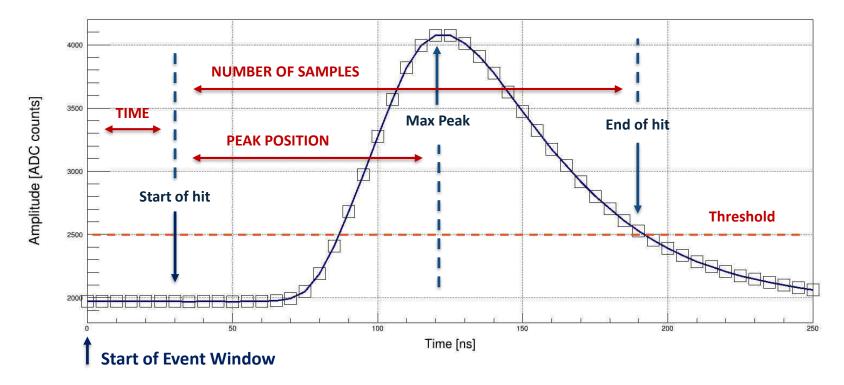
How to Handle the Pileup?



- After the first peak over threshold, if other ones arrive within 17 samples from the moment the waveform goes under threshold, the two hits are merged
 - This allows to save more bandwidth than would be possible separating the hits

6/26/18

Zero Suppression: Pre-Proc



- Other than the value of the samples, we have to store in the hit also some additional info:
 - HIT TIME: the number of clock cycles from the start of the Event Window to the first sample of the hit
 - NUMBER OF SAMPLES: the number of clock cycle from the start to the end of an hit
 - **PEAK POSITION**: the position inside the hit of the absolute maximum of the waveform
 - **ERROR FLAG**: a flag that contains info on the quality of the hit.. It has to be specified yet

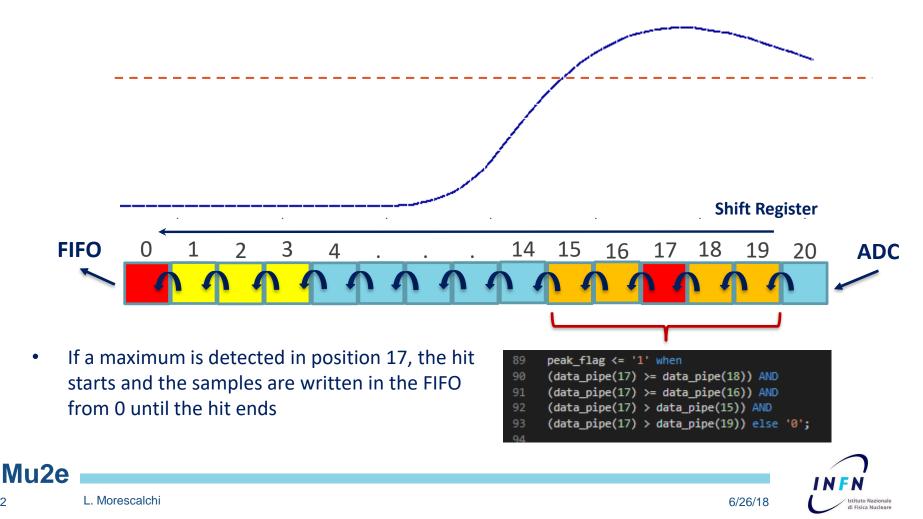


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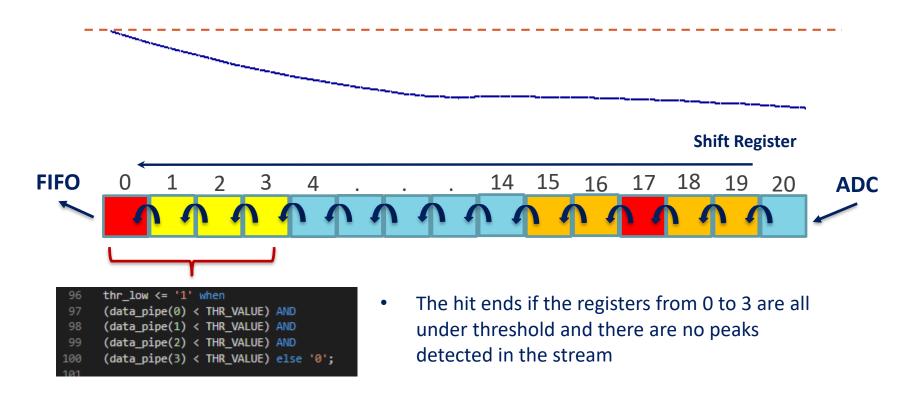
2

Zero Suppression: Implementation

- The sampled waveforms pass through a shifter register, which can be seen as a picture of the samples that updates at every clock cycle
- A sample enters in position 20 and when in position 0 it can be either stored in a FIFO or lost



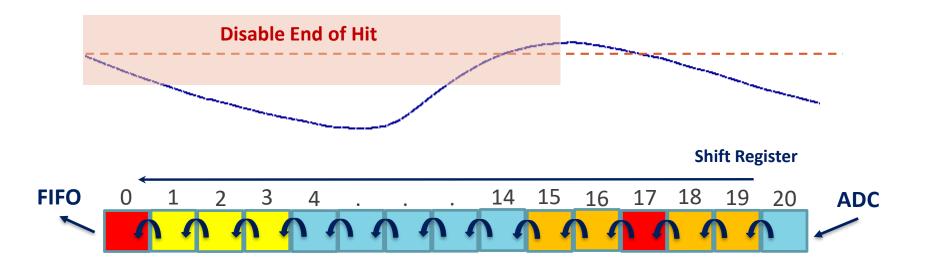
Zero Suppression: Implementation



• Time, Number of Samples, Position of the Peak and Error Flag are computed while the waveform pass thought the register and are available when the hit ends



Zero Suppression: Implementation

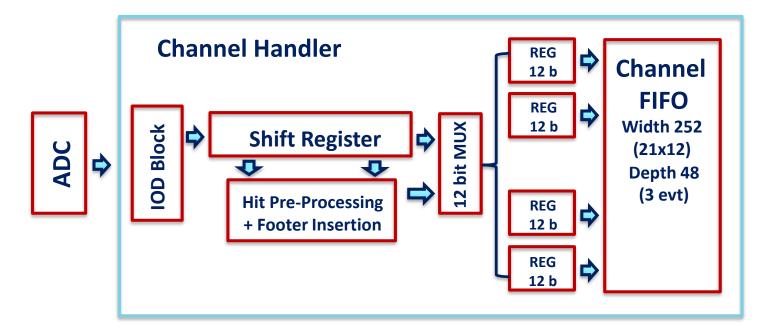


- If a peak is detected in position 17, the 'under threshold' condition is disabled until the peak arrives in position 0
- Afterwards, normal conditions apply



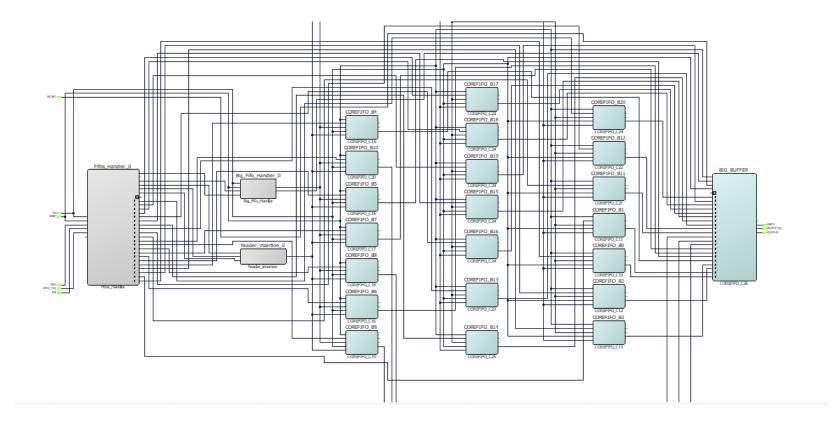
One Channel Pipeline

- To handle the data volume we decided to parallelize as much as possible the flux inside the FPGA
- The DDR memory is 32 bit wide with an operating frequency of 1333 MHz but it can be seen at the firmware level as a larger and slower memory : 256 bits with 166 MHz clock frequency -> 21 samples (12 bit wide) can be written in a single clock cycle



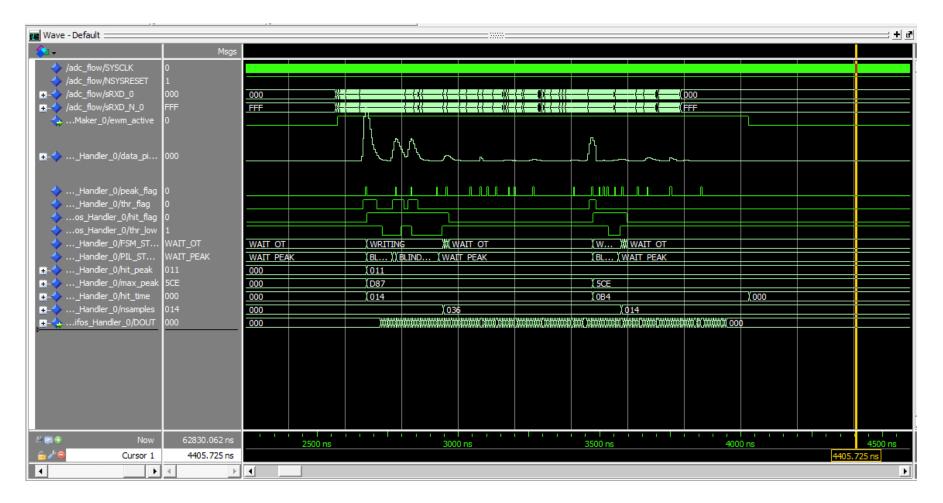


One Channel Firmware





One Channel Simulation



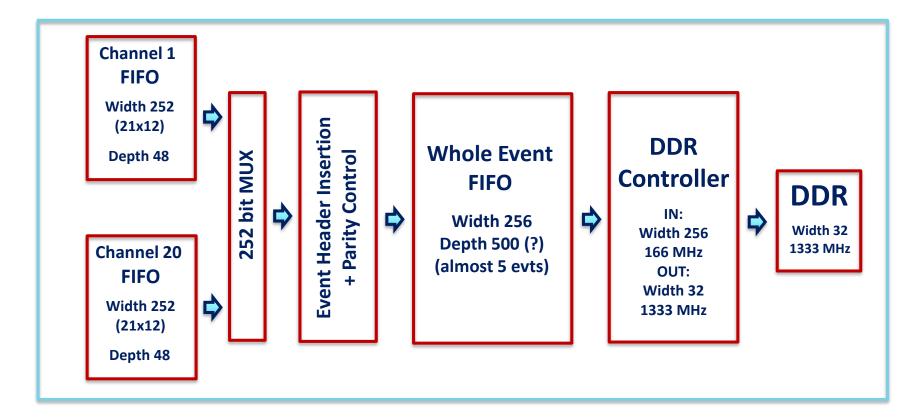
This part is working as expected... •





6/26/18

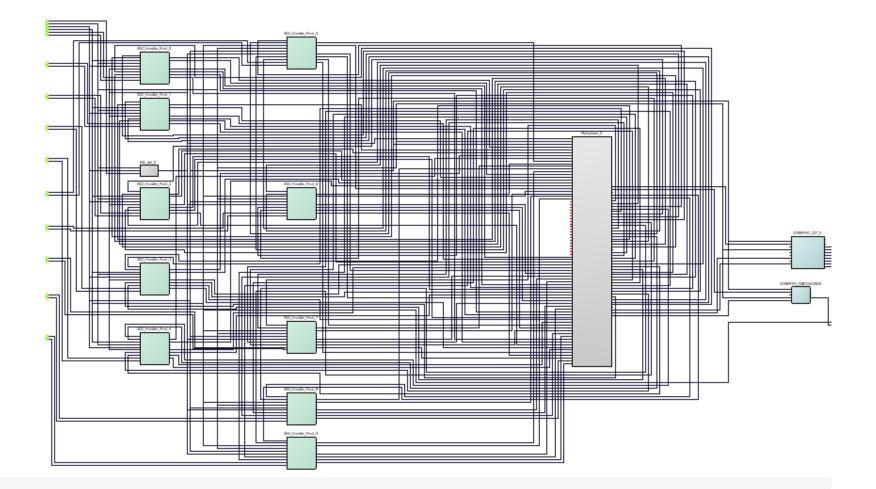
20 Channels Data Pipeline



- Data are conveyed into a 'whole event' FIFO where they are ready to be written in the DDR
- The depth of these FIFO has to be optimized with respect to a realistic simulation of the hit distribution and to the DDR performances (latency, read/write time, arbiter)



20 Channels Firmware





INFN

Istituto Nazionale di Fisica Nucleare



Post-Sinthesys Resources Usage

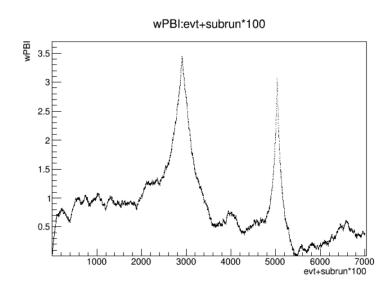
Module Name	Fabric 4LUT	Fabric DFF	Interface 4LUT	Interface DFF	Single-Ended I/O	Differential I/O Pairs	uSRAM 1K	LSRAM 18K	Chip
🗄 Тор	35596	30756	21864	21864	5	133	1	607	21
Primitives	2	0	0	0	5	3	0	0	1
ADC_Block_0	858	1303	720	720	0	130	0	20	11
CLKBUF_DIFF_0	0	0	0	0	0	0	0	0	1
CLKBUF_DIFF_1	0	0	0	0	0	0	0	0	1
CORERESET_PF_C0_0	1	2	0	0	0	0	0	0	0
🖻 Data_Handler_Final	34735	29451	21144	21144	0	0	1	587	4
Primitives	3	0	0	0	0	0	0	0	0
ADC_Handler_F	2963	2832	2088	2088	0	0	0	58	0
ADC_Handler_F	2961	2830	2088	2088	0	0	0	58	0
ADC_Handler_F	2961	2830	2088	2088	0	0	0	58	0
ADC_Handler_F	2961	2830	2088	2088	0	0	0	58	0
ADC_Handler_F	2960	2830	2088	2088	0	0	0	58	0
ADC_Handler_F	2961	2830	2088	2088	0	0	0	58	0
ADC_Handler_F	2962	2830	2088	2088	0	0	0	58	0
ADC_Handler_F	2960	2830	2088	2088	0	0	0	58	0
ADC_Handler_F	2961	2830	2088	2088	0	0	0	58	0
ADC_Handler_F	2961	2830	2088	2088	0	0	0	58	0
COREFIFO_C27_0	188	290	252	252	0	0	0	7	0
COREFIFO_NBI	21	23	12	12	0	0	1	0	0
EW_del_0	0	25	0	0	0	0	0	0	0
Inganno_0	23	0	0	0	0	0	0	0	0
Inganno_1	21	0	0	0	0	0	0	0	0
Inganno_2	21	0	0	0	0	0	0	0	0
Inganno_3	21	0	0	0	0	0	0	0	0
Inganno_4	21	0	0	0	0	0	0	0	0
Inganno_5	21	0	0	0	0	0	0	0	0
Inganno_6	21	0	0	0	0	0	0	0	0
Inganno_7	21	0	0	0	0	0	0	0	0
Multi8_0	8	0	0	0	0	0	0	0	0
Multiplexer 0	4734	811	0	0	0	0	0	0	4



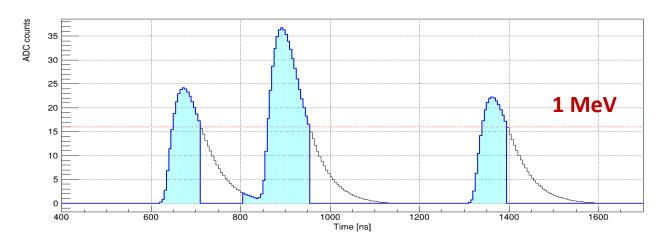
2



Stress Test Simulation: Dataset



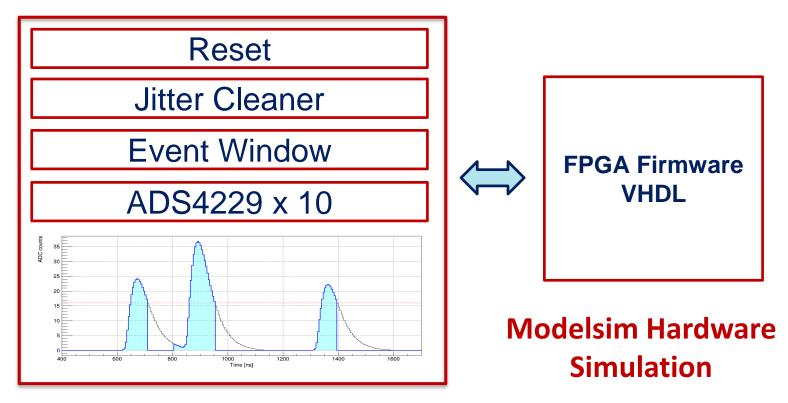
- S. Werkema produced about 43.5 ms of beam intensity fluctuation and Kutschke simulated around 12 ms (7000 evts) of them
- The information regarding the calorimeter have been extracted and the waveforms have been constructed with the new signal shape
- An event list with about 7k evts has been prepared using the board with more occupancy





Stress Test Simulation: Testbench

To test this firmware implementation we setup a testbench using a realistic digital ۲ simulation that includes the expected hit distribution for each channel and the luminosity fluctuation



VHDL for external DDR modules is missing! ۲



2

Stress Test Simulation: Results

Wave - Default	
🔔 - Msgs	
/Multiplexer_0/CLK 0	
0/Multiplexer_0/EW 0	
ltiplexer_0/ch2read 0	
🖕ltiplexer_0/DWRITE 0	<u>1911 - 1919 10 - 1917 11 - 1917 11 - 1919 11 - 1919 11 - 1917 11 - 1917 11 - 1917 11 - 1917 11 - 1917 11 - 191</u> 999
🖕plexer_0/BWWRITE 0	
	ου τοο τοο τοο τοο τοο τοο τοο τοο τοο τ
exer_0/HIT_MAP_0 1	1 X X X 2 XX X X X X X X X X X X X X X X
	2 10 11 X/1 X0 X1 X2 X0 XX3 X0 X1 X0 X0 X1 X0 X0 X1 X0
	<u>(2 10 X1 X0 X1 XX2 X0 X1 X0 X2 X0 X1 X0 X1 X0 X1 X0 X1 X1X2 X0 X1 X2 0 X1 X0 X1 X0 </u>
exer_0/HIT_MAP_3 2	(1 ½ 1½ ½ ½ ½ ½½ ½½ ½½ ½½ ½½ ½½ ½½ ½½ ½½
exer_0/HIT_MAP_4 2	
. exer_0/HIT_MAP_5 1	
exer_0/HIT_MAP_6 3	
exer_0/HIT_MAP_8 3	
xer_0/HIT_MAP_10 1	
xer_0/HIT_MAP_11 0	
xer_0/HIT_MAP_12 0	
xer_0/HIT_MAP_13 2	
xer_0/HIT_MAP_17 0	
•	
xer_0/HIT_MAP_19 1	
▲■● Now 288982.51 ns	10000 ns 15000 ns 20000 ns 25000 ns 30000 ns 35000 ns
69895.777 ns	

• Have been used 100 events in the worst region around the peak of the luminosity



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2

FIFO Content Check

🚟 L	ist												
File	Edit V	/iew	Add	Tools	Bookmarks	Window	Help						
List - Default													
	- 🚅 🛯		- 1	V 🗈	• @	- M							
	· 🖉 🛛		P Konstrij	d0	=		- E3						
ps/adc_flow/CortexM1_Subsystem_0/Data_Handler_Final_0/Multiplexer_0/Q													
delta													
/a c flow/CortexMI_Subsystem_0/Data_Handler_Final_0/Multiplexer_0/DWRITE											1		
53	346677	+6		81F8	2182301E01	101F555FF	F80F811	81381481	681881E	81D81F8	2182301E	2011 1	
53	351677	+6		0000	0000000000	000000000	0000000	00000000	0000000	0000000	0000000	0000 0	
53	376677	+6		81D8	1F82101E01	10AE81B81	A818815	81280D80	7803800	8008008	00800800	800 1	
53	381677	+6		8178	1881A81B81	C81C01B01	103D555	FFF80F81	0812814	8158178	1881A81E		
53	386677	+6			00000000000								
-	406677	+6			1F82101E01								
-	411677	+6			1881A81B81								
	416677	+6			0000000000								
	481677	+6			1981A81B81								
	486677	+6			1981B81C81								
-	491677	+6			1981B81C81								
-	496677	+6			00000000000								
	516677 521677	+6 +6			0F81081081 4F85385685								
	526677	+6			4r05305005 1981B81D81								
	531677	+6			2682982C82								
	536677	+6			2682903E01								
	541677	+6			000000000000000000000000000000000000000								
	561677	+6			1881A81B81								
	566677	+6			1C81E81F82								
55	571677	+6		81A8	1C81E81F01	D01105E55	5FFF80E	81081181	3815817	81981A8	1C81E81E	701D 1	
55	576677	+6		0000	0000000000	000000000	0000000	00000000	0000000	0000000	00000000	0000 0	
55	596677	+6		8178	1881A81B81	C81C82081	F81D81A	81681180	B806804	8048048	04805806	5806 1	
56	601677	+6		81A8	1C81E81F82	082005E55	5FFF80E	81081181	3815817	81981A8	LC81E81E	820 1	
56	606677	+6		81A8	1C81E81F01	D01105E55	5FFF80E	81081181	3815817	81981A8	1C81E81E	701D 1	
56	611677	+6		0000	0000000000	000000000	0000000	00000000	0000000	0000000	0000000	0000 0	
56	631677	+6			1981A81B81								
	636677	+6			1981B81C81								
	641677	+6			1981B81C81								
	646677	+6			0000000000								
50	666677	+6		81F8.	2182301E01	101F82081	F81C819	81480F80	9803801	8008008	00800800	0800 1	
			4										

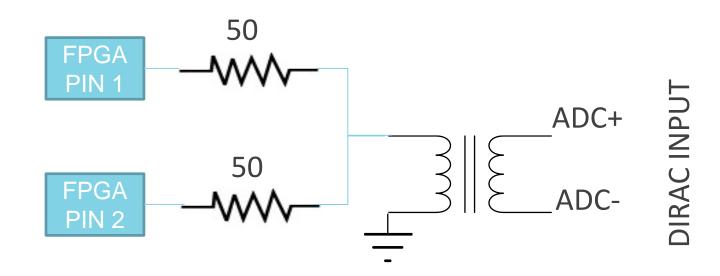
- The FIFO has been filled without any bottleneck..
- To check the content we need a dedicated C++ simulation that reproduces the 256 bits words starting from the same text files
 - Script under development
- It remains to be seen if we are able to empty the FIFO and write into the external DDR at the right rate
 - The DDR clock is 166 MHz and not 200 MHz
 - Tracker group reported a big latency in the read/write operation
 - The VHDL model for the DDR is not available
- We are keeping the possibility open to pass from DDR3 to DDR4



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Hardware Stress Test

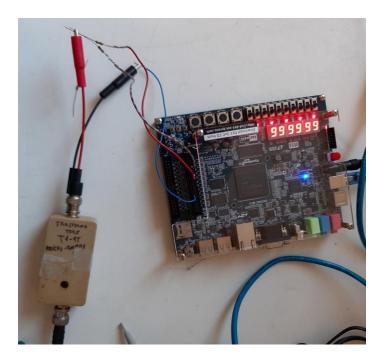
- To validate data bandwitdh in the DIRAC we don't need real waveforms.
- Square waves connected to the ADC inputs (V > THR) are enough and are easy to generate through digital outputs of an FPGA demo board.
- The algorithm uses the first peak as start for taking data so we plan to use 2 levels square waves to emulate real signals.

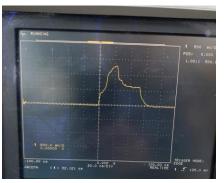


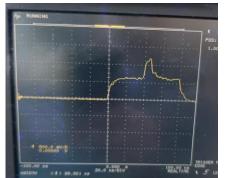


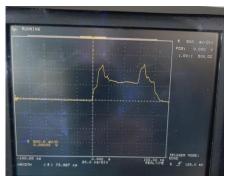
Hardware Stress Test

 Antonio has written a macro to convert the root file to a text file to fill a memory inside the pattern generator FPGA (includes 128 event windows) pattern generator FPGA





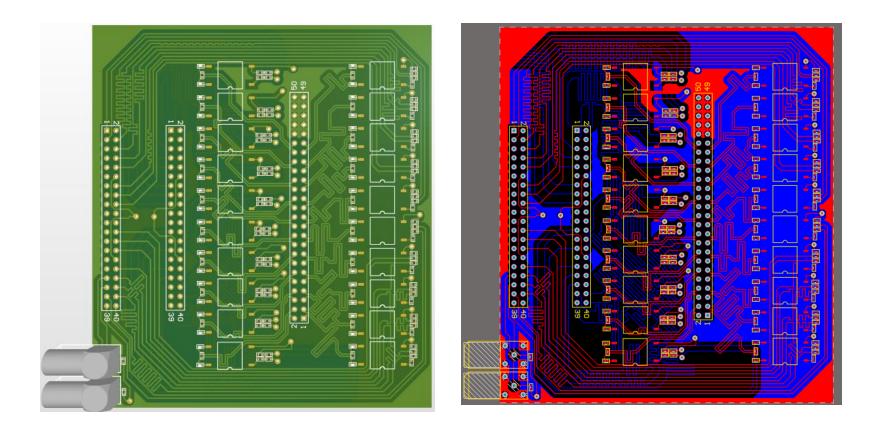








Hardware Stress Test



• Interface to DIRAC, include transformers to convert single ended digital signals to differential





Summary

- We completed a first version of the firmware that includes the interface with the DTC, the interface with the RAM and the final packaging of data
- The data flow inside the FPGA has been studied and a first version of this part of the firmware has been written and simulated using a realistic digital simulation that includes the expected hit distribution for each channel and the luminosity fluctuation
 - So far the FPGA seems to substain the data flux, but the VHDL model of external DDR is missing
- Same data stream can be used to stress test the real hardware using as waveform generator an FPGA demo board
 - > All the materials for the test have been purchased



